

Docket No.: 065326-0029

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	Customer Number: 20277
Yasushi SASA, et al.	:	Confirmation Number: 9832
Application No.: 10/657,107	:	Group Art Unit: 2624
Filed: September 09, 2003	:	Examiner: Alex Kok Soon LIEW
For: DEFECT INSPECTION APPARATUS, DEFECT INSPECTION METHOD AND PROGRAM	:	

CORRECTED INFORMATION DISCLOSURE STATEMENT

Mail Stop IDS
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

The corrected Information Disclosure Statement is being filed after the filing of the Information Disclosure Statement on May 18, 2007, to correct the PTO-1449 form filed with the Information Disclosure Statement. A corrected PTO-1449 is filed herewith. Please note the Publication Date for JP 04-107945 should appear as 04-09-1992 and NOT 04-09-1995.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

McDERMOTT WILL & EMERY LLP



Stephen A. Becker
Registration No. 26,527

600 13th Street, N.W.
Washington, DC 20005-3096
Phone: 202.756.8000 SAB:JGH
Facsimile: 202.756.8087
Date: August 27, 2007

**Please recognize our Customer No. 20277 as
our correspondence address.**

INFORMATION DISCLOSURE CITATION IN AN APPLICATION CORRECTED (PTO-1449)				ATTY. DOCKET NO. 065326-0029		SERIAL NO. 10/657,107	
				APPLICANT Yasushi SASA, et al.			
				FILING DATE September 09, 2003		GROUP 2624	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
		US					
		US					
		US					
		US					
		US					
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes -Number 4 -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes No	
		JP 04-107945	04-09-1992	HITACHI LTD; HITACHI TOKYO ELECTRON CO LTD		JAPAN (w/English abstract)	
		JP 07-027711	01-31-1995	ASIA ELECTRON INC		JAPAN (w/English translation of abstract, claims and specification)	
		JP 09-236487	09-09-1997	NEW JAPAN RADIO CO LTD		JAPAN (w/English translation of abstract, claims and specification)	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
		Japanese Office Action issued in corresponding Japanese Patent Application No. JP 2002-294851, dated April 18, 2007					
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.